

L Number	Hits	Search Text	DB	Time stamp
-	639	object with method with exercise	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/08 15:18
-	3	(object with method with exercise) and (((717/124,125,127,131) or (702/108,117,119) or (712/220,227)).CCLS.)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/08 15:15
-	236	(object with method same test\$3) and (((717/124,125,127,131) or (702/108,117,119) or (712/220,227)).CCLS.)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/08 15:18
-	2304	object with method same test\$3 same (cho\$3 selec\$4 input\$4)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/08 15:21
-	71	(object with method same test\$3 same (cho\$3 selec\$4 input\$4)) and (((717/124,125,127,131) or (702/108,117,119) or (712/220,227)).CCLS.)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/08 15:35

-	49	( "6178545" "5815710" "6219717" "6219717" "4413386" "5241673" "5276816" "5396614" "5422139" "5579518" "5687303" "5737554" "5740440" "5752034" "5757971" "5805736" "5822460" "5822587" "5883977" "5912665" "5978582" "5978031" "6006013" "6049567" "6052525" "6055337" "6081808" "6085035" "6144409" "4553841" "4903202" "4905148" "4979314" "5008623" "5305430" "5339438" "5418964" "5421016" "5471399" "5471596" "5513343" "5537630" "5551035" "5579309" "5590261" "5604907" "5632034" "5633685" "5676860" "5687210") .pn.	USPAT	2004/06/09 07:43
-	17904	object with method same test\$3	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2004/06/09 08:01

-	2	(corba com rmi) and ((6178545" "5815710" "6219717" "6219717" "4413386" "5241673" "5276816" "5396614" "5422139" "5579518" "5687303" "5737554" "5740440" "5752034" "5757971" "5805736" "5822460" "5822587" "5883977" "5912665" "5978582" "5978031" "6006013" "6049567" "6052525" "6055337" "6081808" "6085035" "6144409" "4553841" "4903202" "4905148" "4979314" "5008623" "5305430" "5339438" "5418964" "5421016" "5471399" "5471596" "5513343" "5537630" "5551035" "5579309" "5590261" "5604907" "5632034" "5633685" "5676860" "5687210").pn. )	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/09 08:02
-	1225	(corba com rmi) and (object with test\$3)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/10 08:24
-	6936	(corba com rmi) and ((object method) with test\$3)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/09 08:03
-	192	(corba com rmi) same ((object method) with test\$3)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/09 08:04
-	43	(corba com rmi) same ((object method) with test\$3) same (invo\$6 exerci\$3 execut\$3)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/09 08:06
-	0	6633888.URPN.	USPAT	2004/06/09 10:05

-	0	cocreatable	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/09 12:47
-	48	cocreat\$4	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/09 13:26
-	2	"20020066079"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/09 13:26
-	3	component and COM with test same log	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/10 08:09
-	1	COM same object with test same log	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/10 08:10
-	203	object with test same log	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/10 08:10
-	203	(object with test same log) and (object with test same log)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/10 08:10
-	7	(object with test same log) and (((717/124,125,127,131) or (702/108,117,119) or (712/220,227)).CCLS.)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/10 08:10
-	15	(US-6523169-\$ or US-6421822-\$ or US-5794043-\$ or US-5590330-\$ or US-4187540-\$ or US-6178545-\$ or US-5551035-\$ or US-5537630-\$ or US-5471596-\$ or US-5421016-\$ or US-5276816-\$ or US-6633888-\$ or US-6505342-\$ or US-5978940-\$ or US-6067639-\$).did.	USPAT	2004/06/10 08:23
-	2	com and ((US-6523169-\$ or US-6421822-\$ or US-5794043-\$ or US-5590330-\$ or US-4187540-\$ or US-6178545-\$ or US-5551035-\$ or US-5537630-\$ or US-5471596-\$ or US-5421016-\$ or US-5276816-\$ or US-6633888-\$ or US-6505342-\$ or US-5978940-\$ or US-6067639-\$).did.)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/10 08:24
-	4	(corba same com same rmi) and (object with test\$3)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/10 08:27
-	6	(corba same com same rmi) and (object with (test\$3 exercis\$3 verif\$7))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/10 08:27
-	266	COM with (javabean bean)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/10 12:39

	2918	((717/124,125,127,131) or (702/108,117,119) or (712/220,227)).CCLS.	USPAT; US_PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT	2004/06/10 12:39
	15	(US-6523169-\$ or US-6421822-\$ or US-5794043-\$ or US-5590330-\$ or US-4187540-\$ or US-6178545-\$ or US-5551035-\$ or US-5537630-\$ or US-5471596-\$ or US-5421016-\$ or US-5276816-\$ or US-6633888-\$ or US-6505342-\$ or US-5978940-\$ or US-6067639-\$).did.		2004/06/10 12:39
	0	(COM with (javabean bean)) and ((US-6523169-\$ or US-6421822-\$ or US-5794043-\$ or US-5590330-\$ or US-4187540-\$ or US-6178545-\$ or US-5551035-\$ or US-5537630-\$ or US-5471596-\$ or US-5421016-\$ or US-5276816-\$ or US-6633888-\$ or US-6505342-\$ or US-5978940-\$ or US-6067639-\$).did.)	USPAT; US_PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/10 12:39
	4	(COM with (javabean bean)) and ((717/124,125,127,131) or (702/108,117,119) or (712/220,227)).CCLS.)	USPAT; US_PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/10 12:40



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Relevance scale **1 OMEN: A strategy for testing object-oriented software**

Amie L. Souter, Lori L. Pollock

August 2000 **ACM SIGSOFT Software Engineering Notes , Proceedings of the International Symposium on Software Testing and Analysis**, Volume 25 Issue 5Full text available:  pdf(329.36 KB)Additional Information: [full citation](#), [abstract](#), [references](#), [citations](#), [index terms](#)

This paper presents a strategy for structural testing of object-oriented software systems with possibly unknown clients and unknown information about invoked methods. By exploiting the combined points-to and escape analysis developed for compiler optimization, our testing paradigm does not require a whole program representation to be in memory simultaneously for testing analysis. Potential effects from outside the component under test are easily identified and reported to the tester. As c ...

**2 Technical correspondence: Embedding built-in tests in hot spots of an object-oriented framework**

Taewoong Jeon, Hyon Woo Seung, Sungyoung Lee

August 2002 **ACM SIGPLAN Notices**, Volume 37 Issue 8Full text available:  pdf(793.62 KB)Additional Information: [full citation](#), [abstract](#), [references](#)

This paper describes a scheme of encapsulating test support code as built-in test (BIT) components and embedding them into the hot spots of an object-oriented framework so that defects caused by the modification and extension of the framework can be detected effectively and efficiently through testing. The test components embedded into a framework in this way increase the testability of the framework by making it easy to control and observe the process of framework testing. The proposed techniqu ...

**Keywords:** built-in test (BIT), hook classes, object-oriented framework, testability

**3 A Methodology of Verification and Testing of Large Software Systems**

V. V. Lipaev

November 2003 **Programming and Computing Software**, Volume 29 Issue 6Full text available:  Publisher SiteAdditional Information: [full citation](#)**4 On built-in test reuse in object-oriented framework design**

Yingwu Wang, Dilip Patel, Graham King, Ian Court, Geoff Staples, Maraget Ross, Mohamad Fayad

March 2000 **ACM Computing Surveys (CSUR)**



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Reliability, IEEE Transactions on , Volume: 37 , Issue: 4 , Oct. 1988

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Yu-Seung Ma; Seung-Uk Oh; Doo-Hwan Bae; Yong-Rae Kwon;

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